

Search Notes

Application/Control No.

10/047,177

Examiner

Erin M. File

Applicant(s)/Patent under
Reexamination

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Art Unit

2634

SEARCHED

Class	Subclass	Date	Examiner
375	229	4/10/2005	EMF
375	232	4/10/2005	EMF
375	290	4/10/2005	EMF
455	296	4/10/2005	EMF

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST US PAT, USPGPUB, EPO, JPO DERWENT, IBM	4/10/2005	EMF
PALM INVENTORSHIP	4/10/2005	EMF